

<b>Notice of References Cited</b>	Application/Control No. 10/791,818	Applicant(s)/Patent Under Reexamination CHANG, SEAN	
	Examiner Matthew Johnson	Art Unit 3682	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,731,588	05-2004	Han, Ming-xing	369/264
*	B	US-7,058,961	06-2006	Han, Ming-xing	720/702
*	C	US-6,747,803	06-2004	Hung, Tech	359/634
*	D	US-3,696,688	10-1972	Goodrich et al.	74/570.2
*	E	US-6,155,134	12-2000	Ikuta et al.	74/570.2
*	F	US-2004/0045397	03-2004	Chang, Sean	074/573.00R
*	G	US-6,477,133	11-2002	Yoshimura et al.	720/702
*	H	US-6,438,094	08-2002	Mahr et al.	369/253
*	I	US-6,580,186	06-2003	Suzuki et al.	310/51
*	J	US-3,866,977	02-1975	Rice, James E.	301/5.1
*	K	US-6,636,469	10-2003	Tomishima, Yuichiro	369/53.14
*	L	US-2004/0013066	01-2004	Oono et al.	369/53.14
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

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